

Abstract Submitted
for the MAR10 Meeting of
The American Physical Society

Development of Low Temperature Scanning Gate Microscope

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[1] M. A. Topinka, et al., *Nature* 410, 183-186 (2001).

[2] A. C. Bleszynski, et al., *Nano Letters* 7, 2559-2562 (2007).

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Date submitted: 17 Nov 2009

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